

Lock-in Imaging Below Diffraction Limit

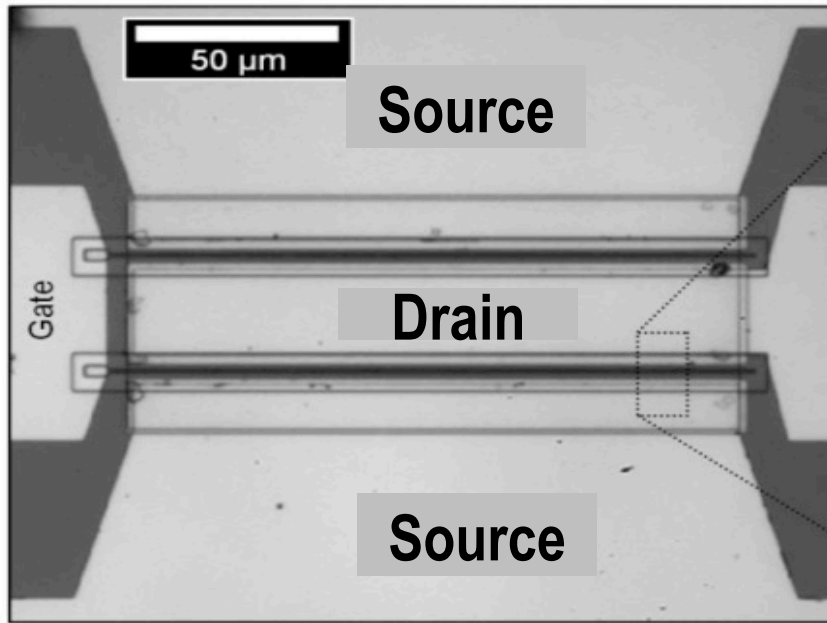
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Birck Nanotechnology Center, Purdue University, IN 47906

Acknowledgement: **Indiana Innovation Institute (IN3)**

Purdue Workshop on Advanced Computational and Quantum Imaging; Sept. 11, 2019



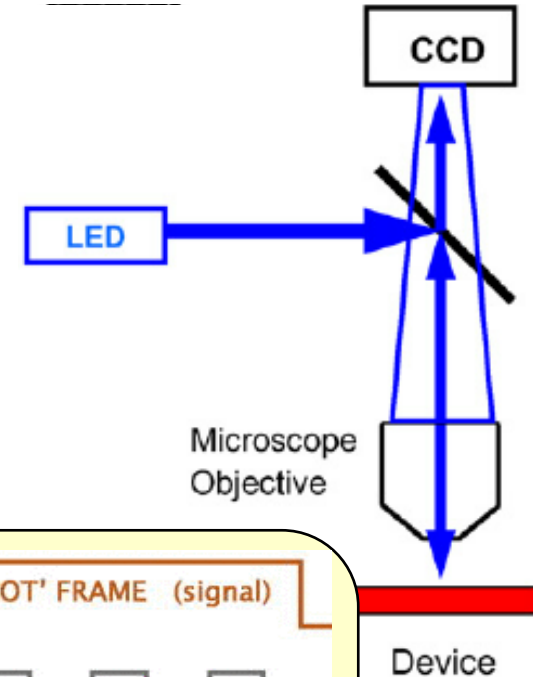
Quantum Engineered Systems & Technology



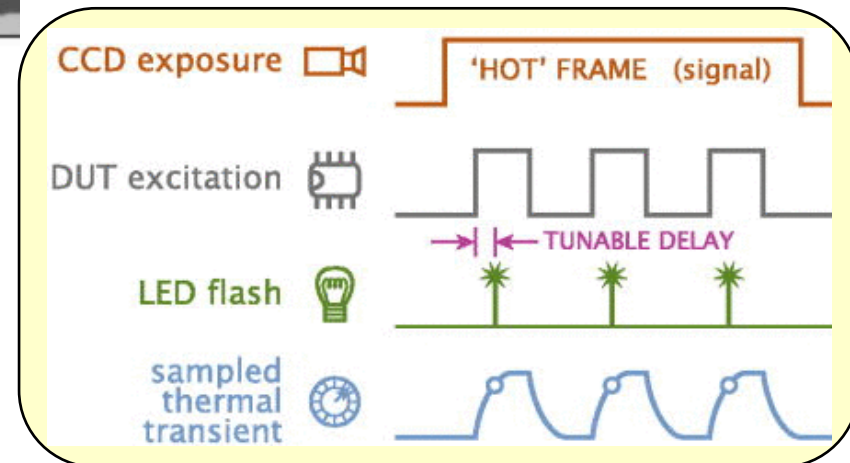
Optical
Image of
GaN HEMT

$$\frac{(\Delta R/R)}{\Delta T} \sim 10^{-4} / \text{C}$$

Mega Pixel Lock-in Camera



- Temp. resolution: **0.01°C**
- Spatial: **100's nm**
- Time: **50ns (800ps)**



J. Christofferson, A. Shakouri, *Rev. of Scientific Instruments*, 2005
K. Yazawa, A. Shakouri, *Electronics Cooling Magazine*, Vol. 3, p.10, March 2011

Transient Thermal Imaging of HEMT

28V,
300mA,
2.19W/mm

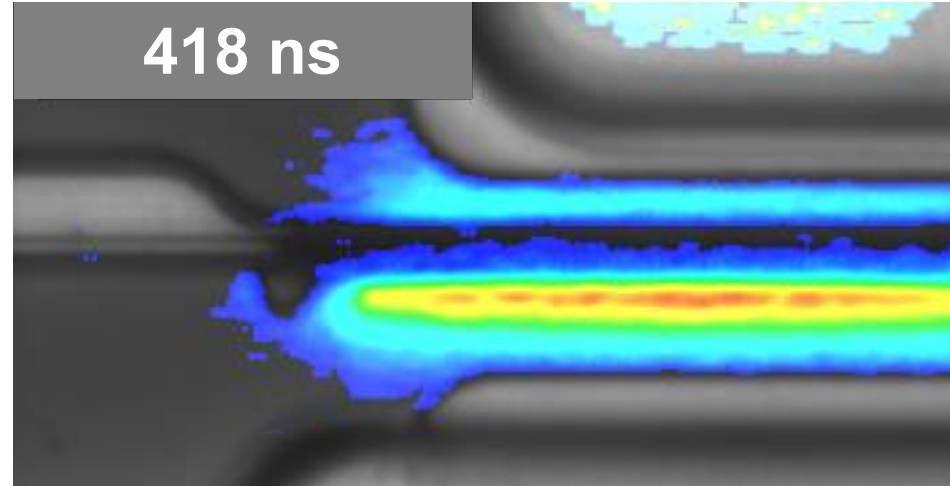
Source

Gate

Drain

GaN High Electron
Mobility Transistor
(HEMT)

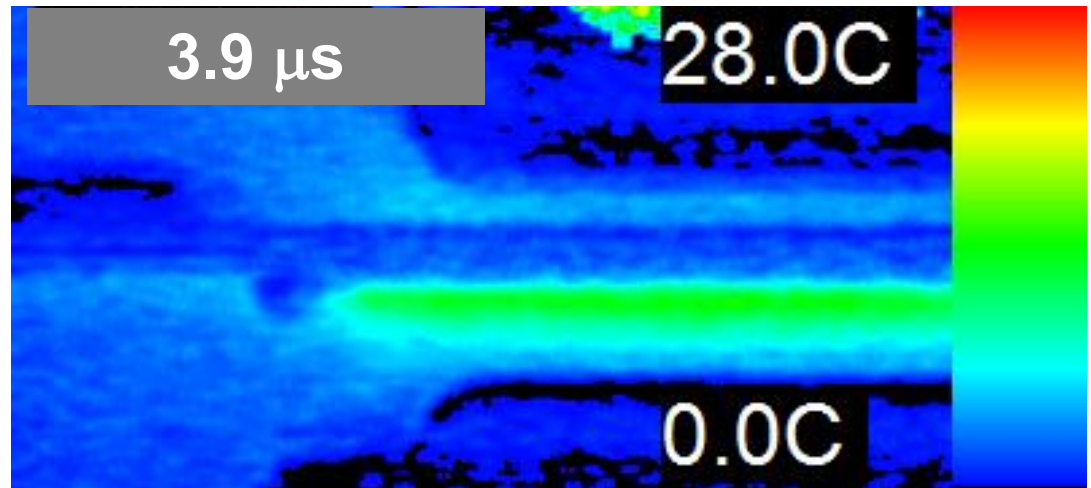
418 ns



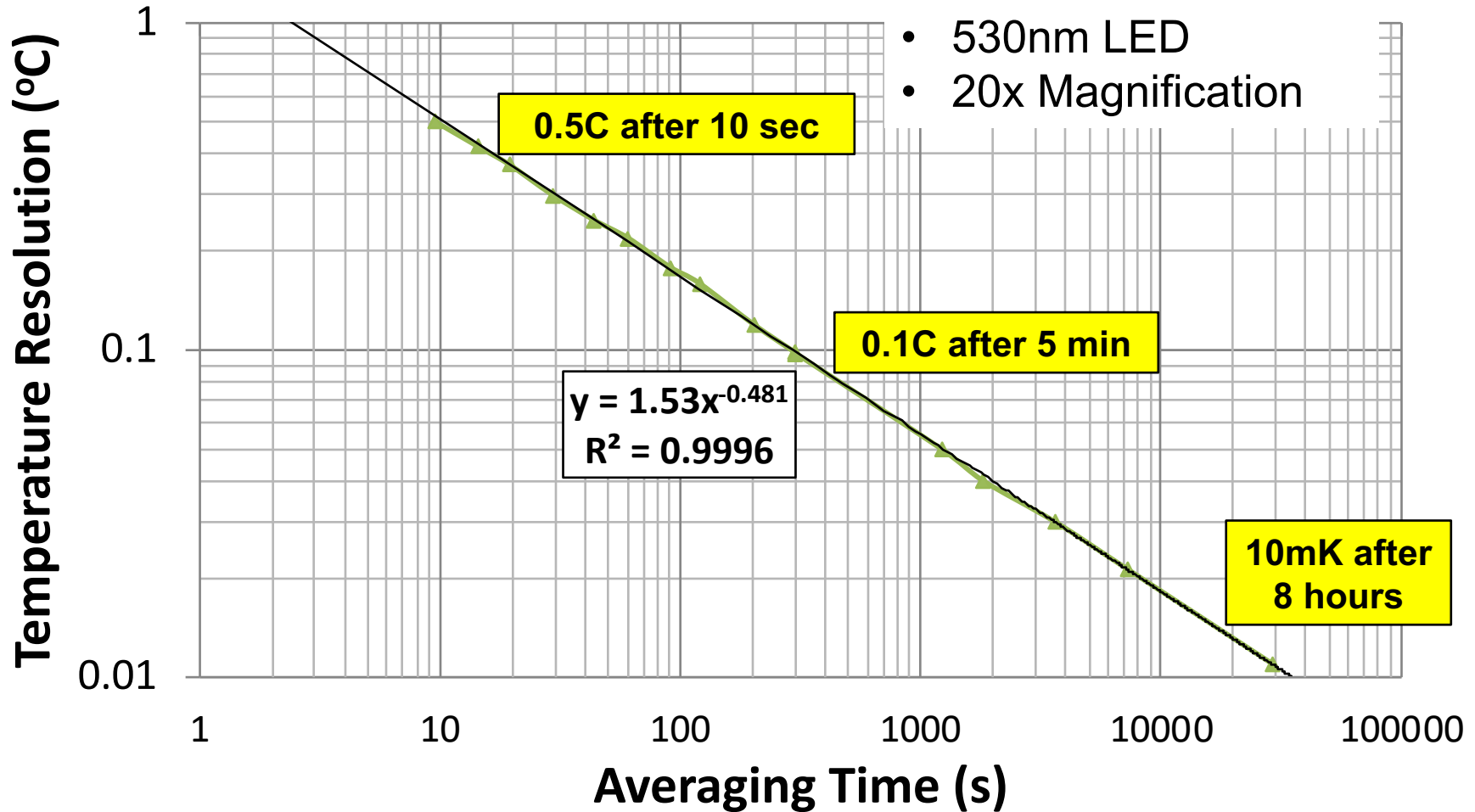
3.9 μ s

28.0C

0.0C



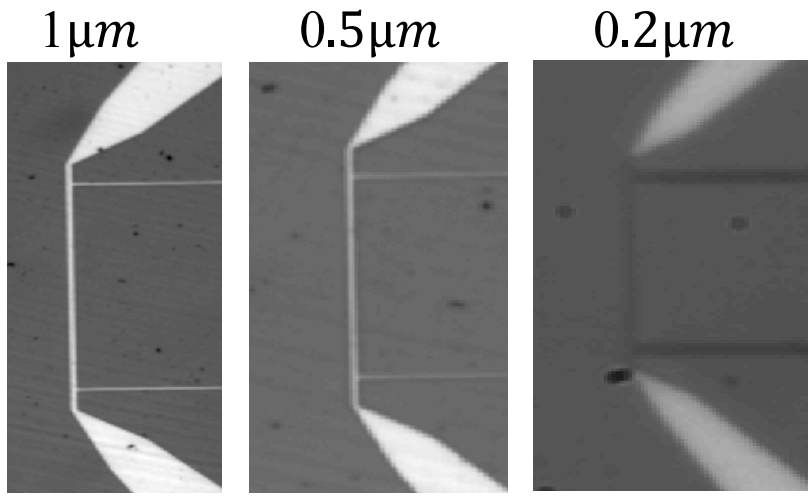
Temperature Resolution



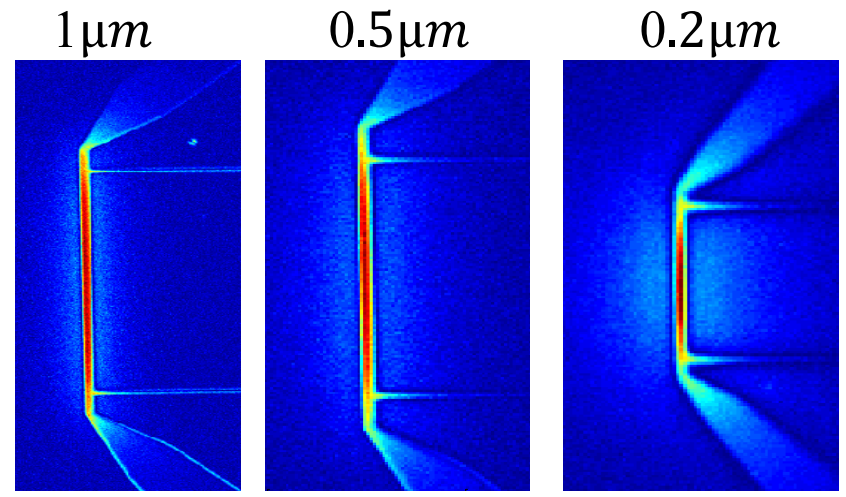
- Temperature resolution on gold region with 8x8 pixels
- Resolution can be improved by $1/\sqrt{t}$ (t is the averaging time)



Sub-Diffraction Thermoreflectance Imaging

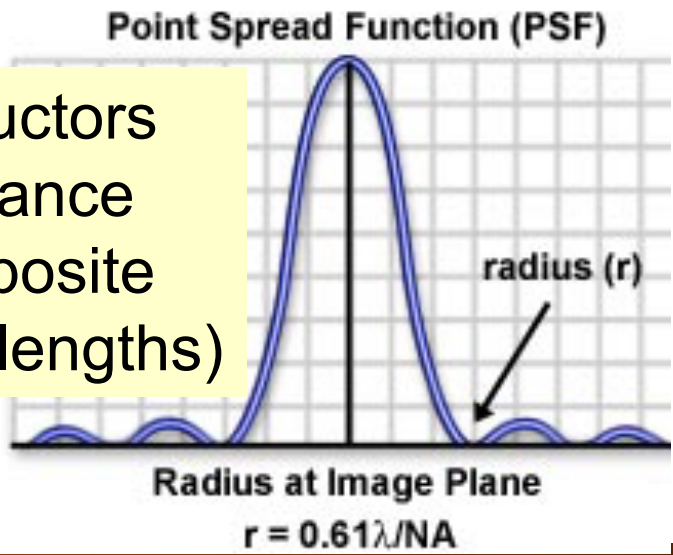


Optical Images



Thermal Images

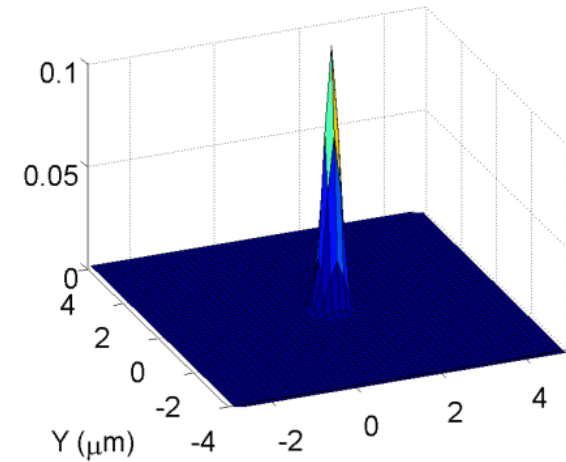
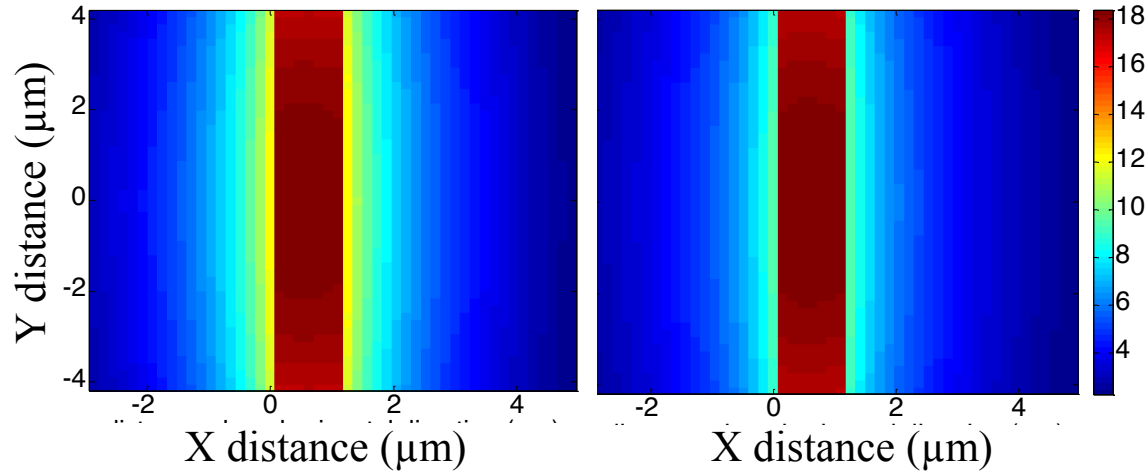
Metals & semiconductors have thermoreflectance coefficients with opposite signs (at certain wavelengths)



Amir Ziabari

<http://www.olympusmicro.com/primer/java/mtf/airydisksize/>

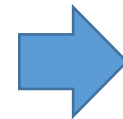




1. ANSYS Temperature Profile for **1 μm device**



2. Temperature profile Normalized by $\text{Au } C_{\text{TR}}$



3. Filtered by Gaussian (Approx. diffraction function)

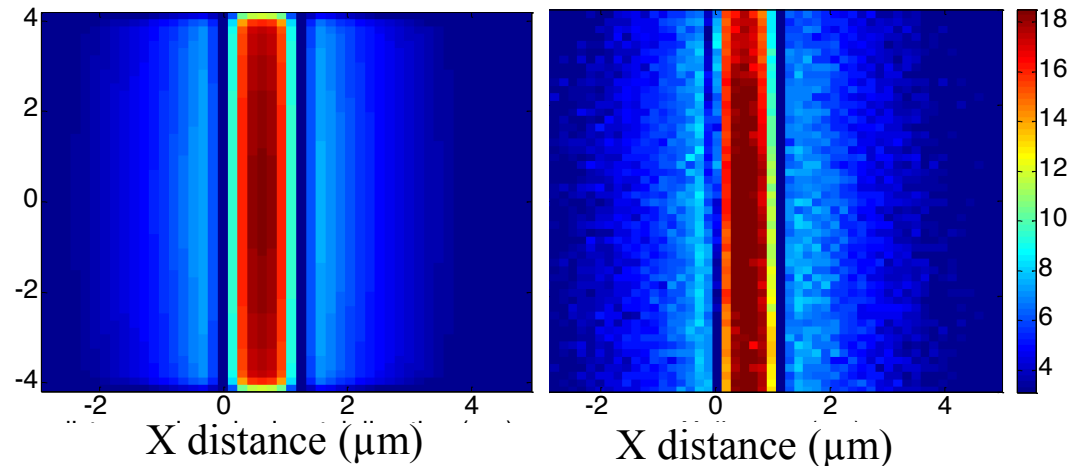
Diffraction can be modelled using image convolution (point spread function)



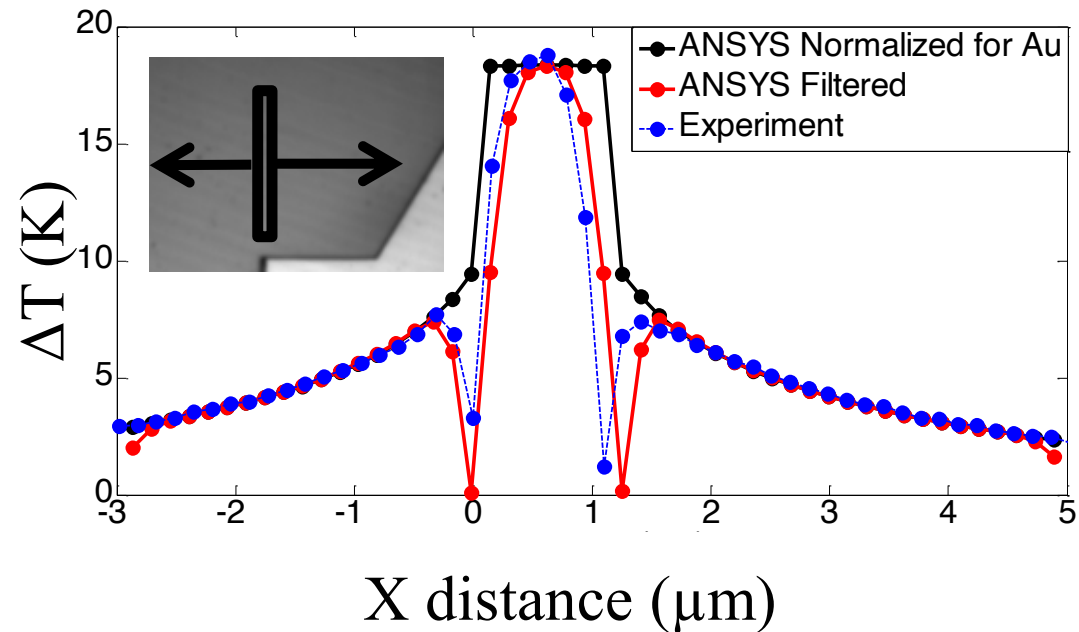
Diffraction (Forward Model) –part II

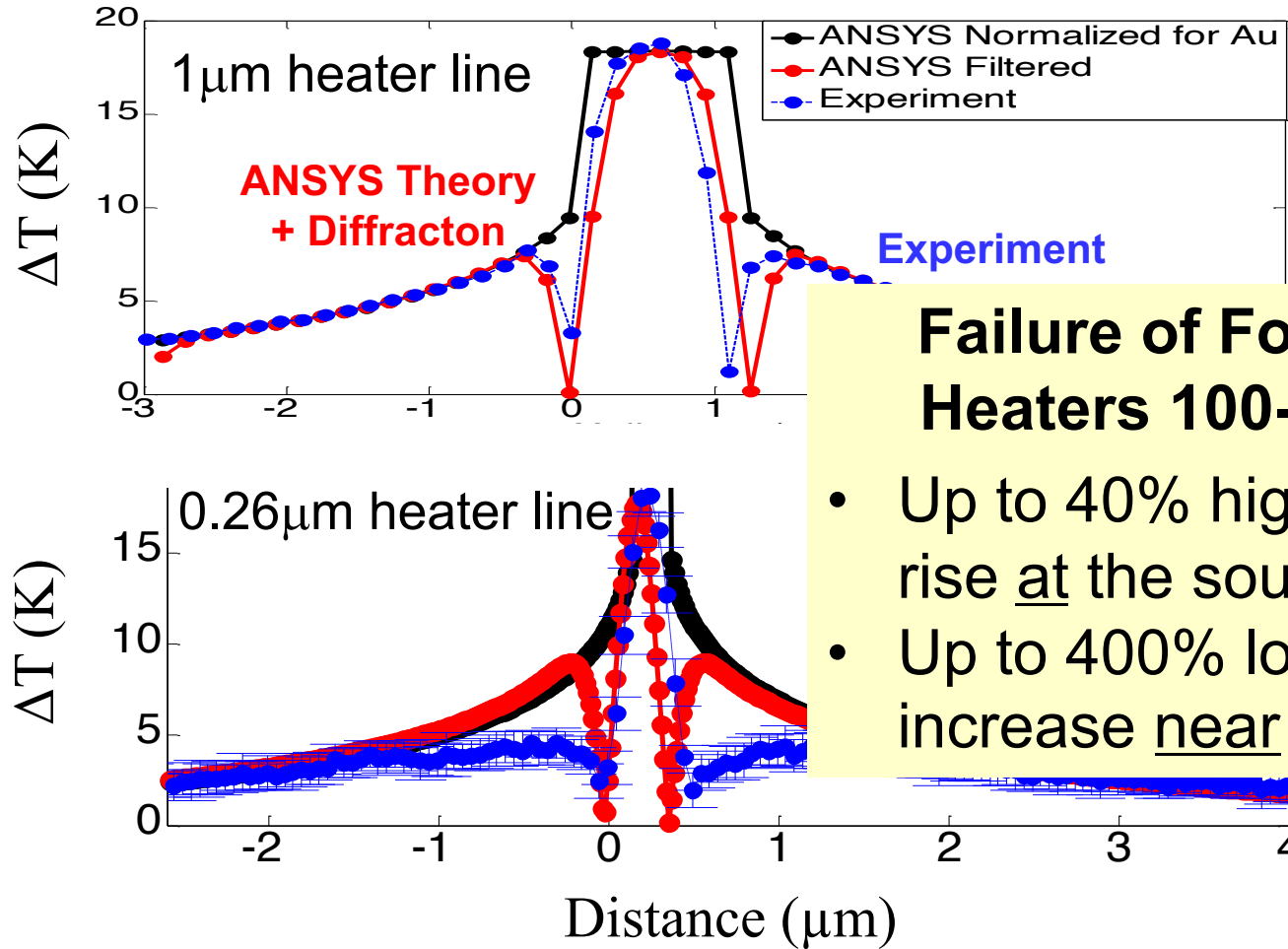
Filtered ANSYS

Experiment



Theory (Fourier heat equation) vs. Experiment for $1\mu\text{m}$ wide Heater Line on InGaAs Substrate





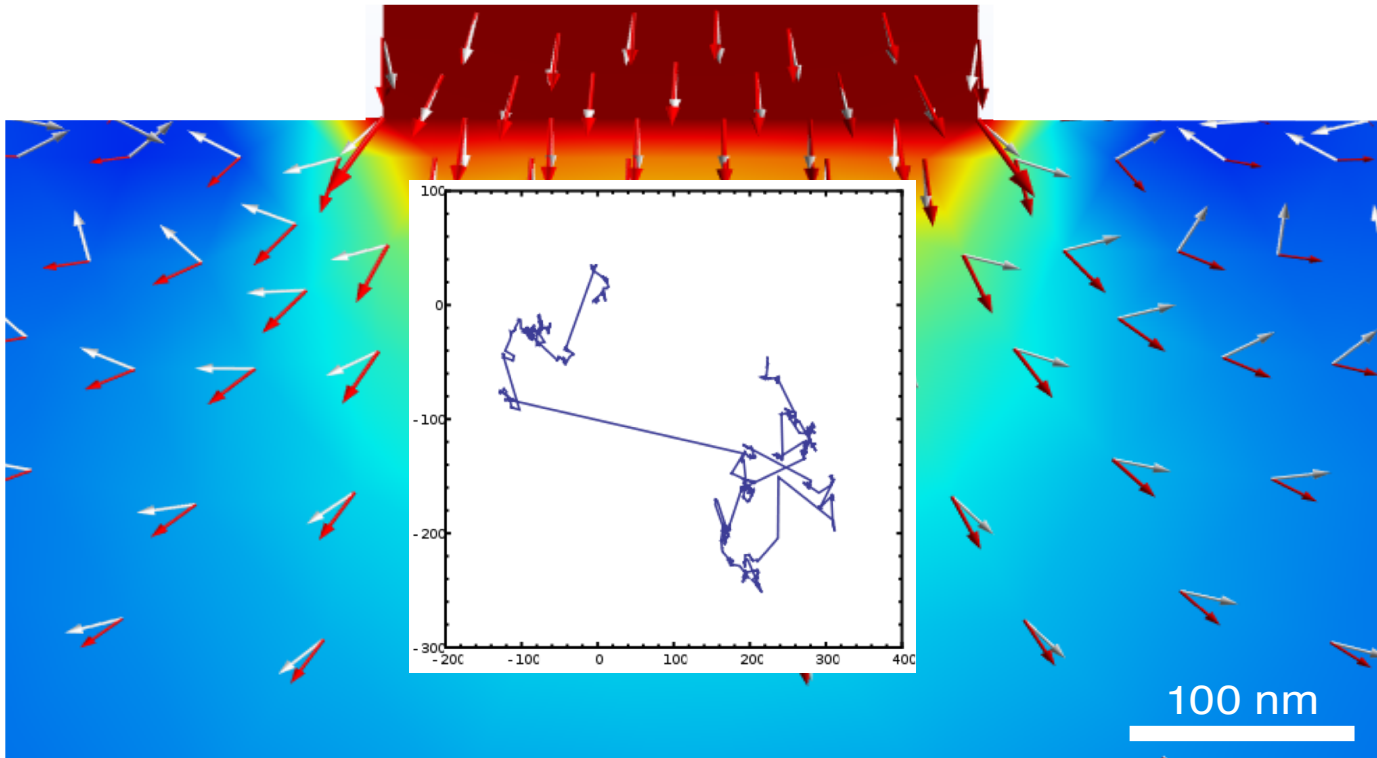
Failure of Fourier Law for Heaters 100-500nm wide:

- Up to 40% higher temperature rise at the source
- Up to 400% lower temperature increase near the source

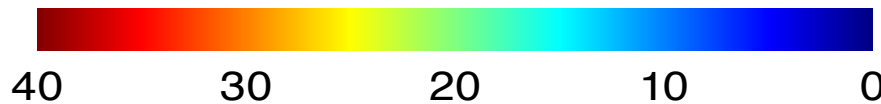


Nanoscale Heat Flow at room T

“small” device ($W = 265\text{nm}$)



Temperature rise (K)



heat flux ↓ minus grad T



Heat
Flux

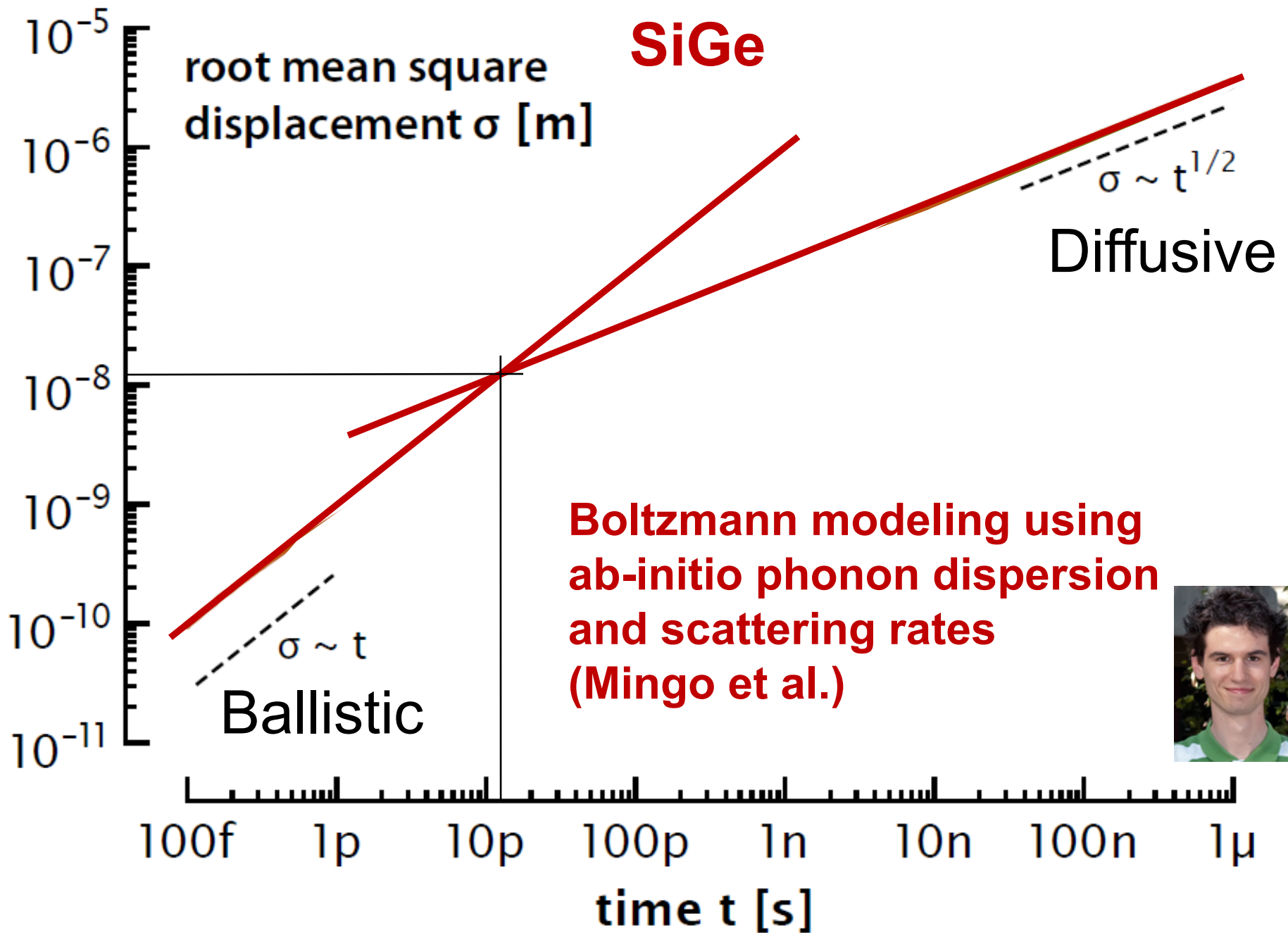
Temperature
Gradient

$$\vec{q} - \underbrace{[l^2 (\nabla^2 \vec{q} + 2\nabla\nabla \cdot \vec{q})]} = -\kappa\nabla T$$

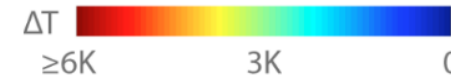
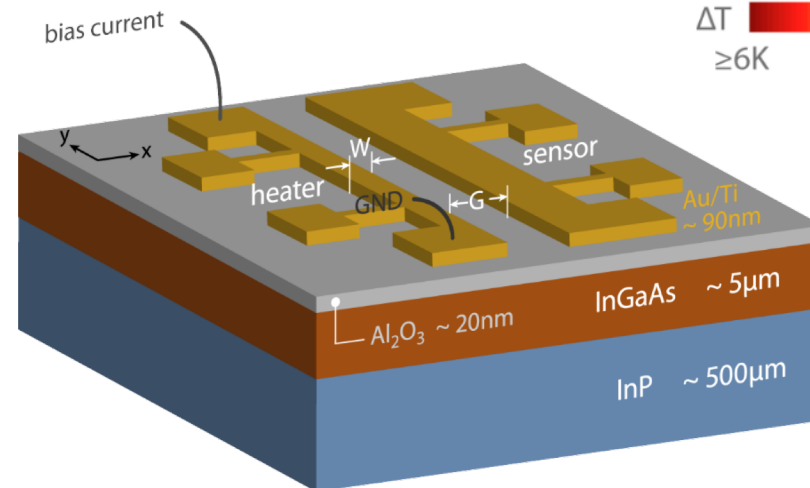
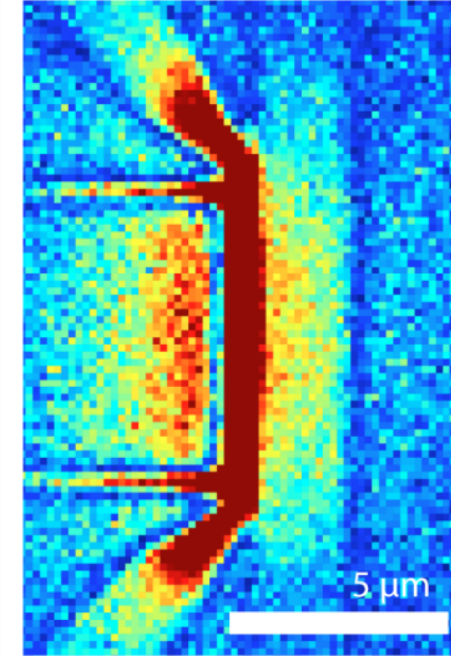
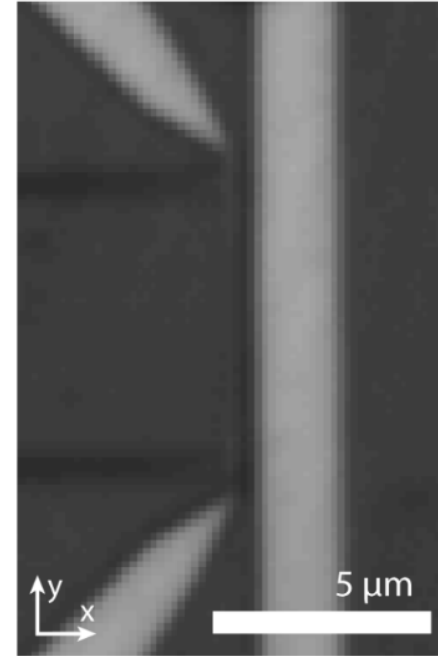
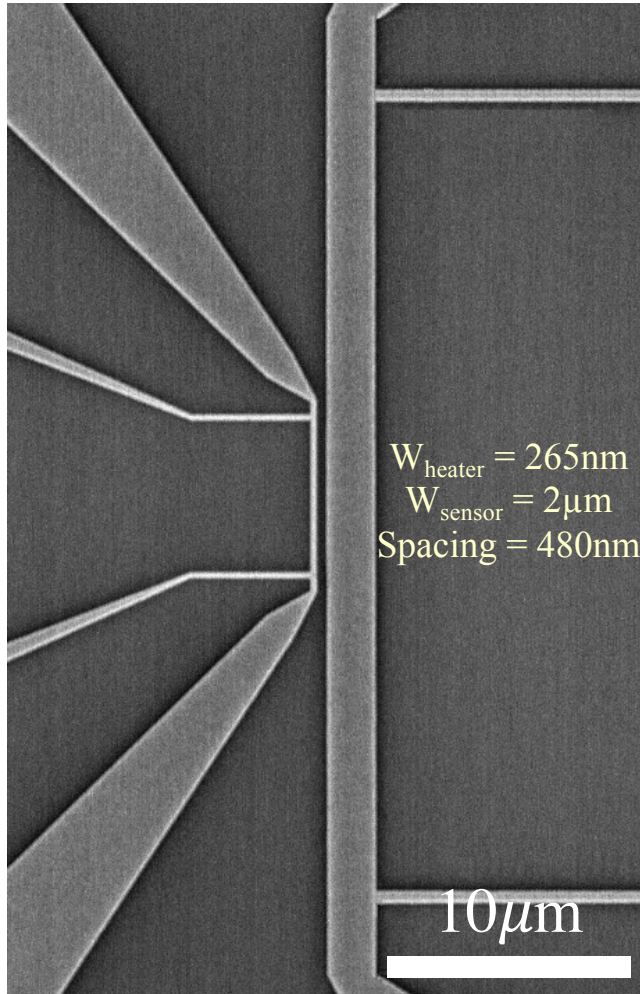
Nonlocality induced by normal phonon scattering and gives rise to hydrodynamic effects over characteristic length l



Xavier Alvarez: Univ. Autonoma de Barcelona



Heater and sensor lines



Sami Alajlouni



$$\hat{f} \leftarrow \operatorname{argmin}_f \left\{ \frac{1}{2\sigma_w^2} \|g - \mathbf{H}f\|^2 + \frac{1}{p\sigma_x^p} \sum_{\{i,j\} \in C} B_{i,j} |f_i - f_j|^p \right\}$$

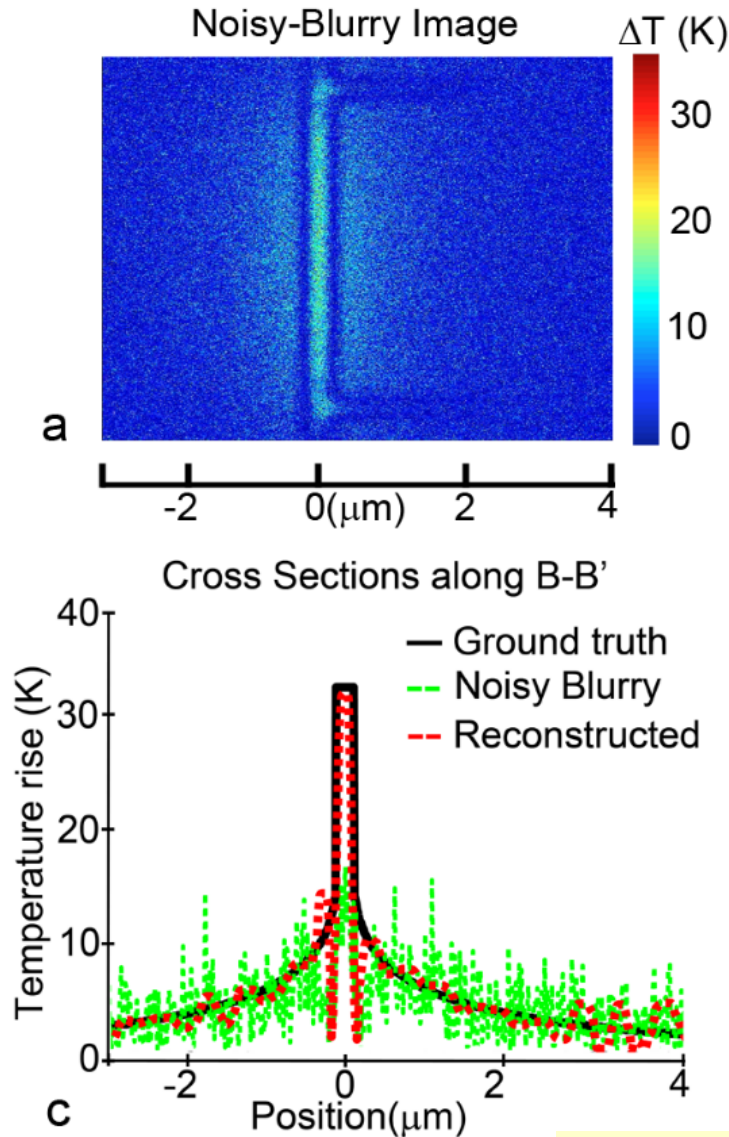
g: measured image
(Blurred and noisy)
H: matrix representation
of the blurring kernel
 σ_w^2 : Noise variance
f: reconstructed image

B: Weight matrix for the
neighborhood pixels
 σ_x : Regularization
 $p \in [1,2]$
C: Neighborhood Clicks

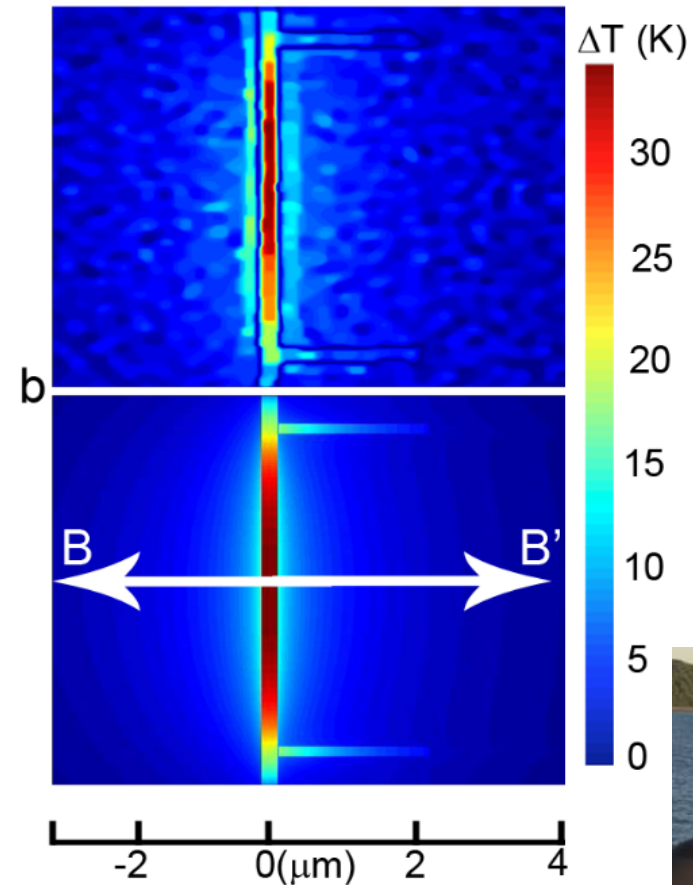
Maximum A-Posteriori (MAP) with non-Gaussian
Markov Random Field



Sub-Diffraction (Inverse Problem)



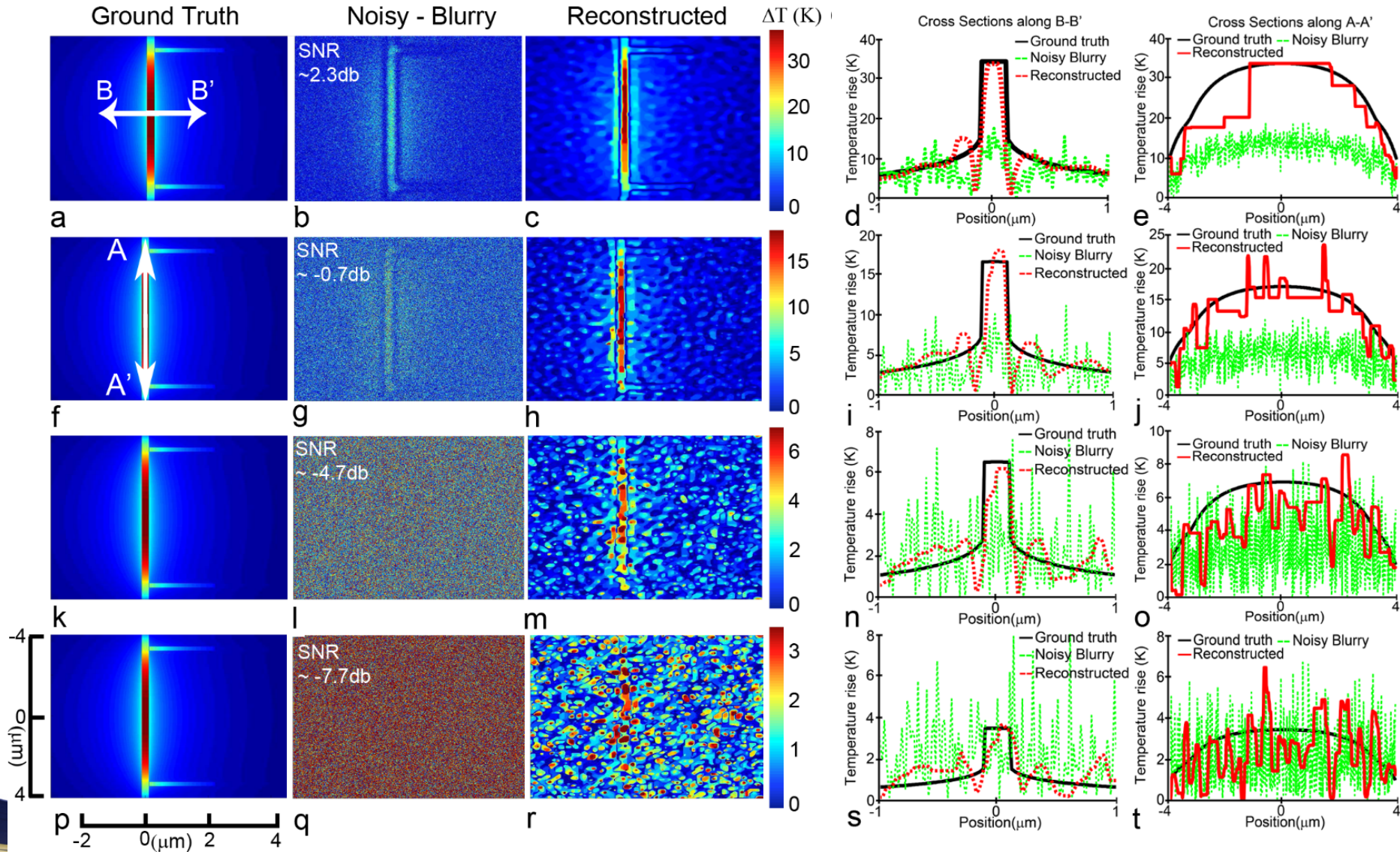
Reconstructed (Top) vs. Ground Truth (Bottom)



Amir Ziabari

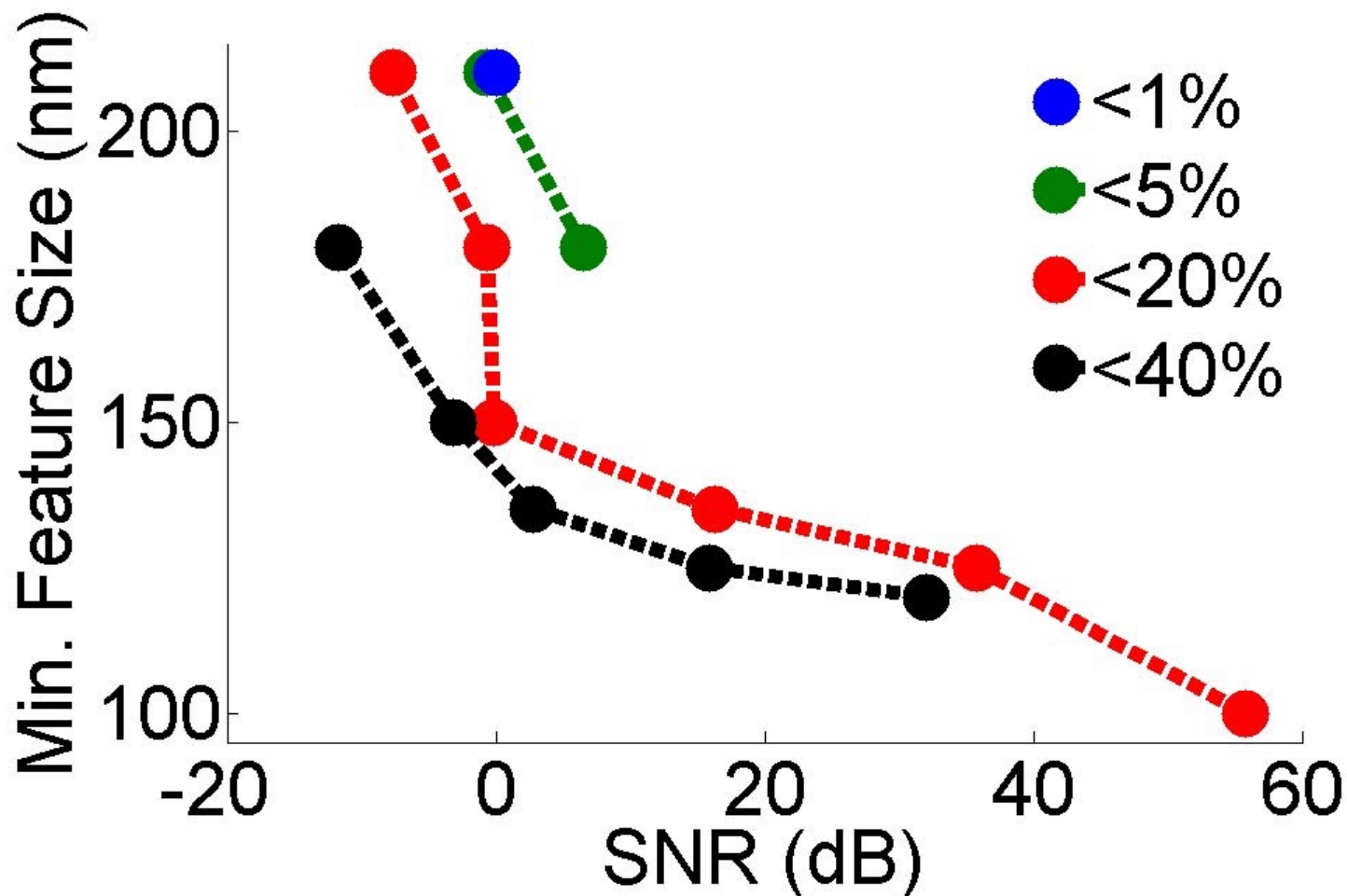
Numerical Experiments

Extracted temperature profile for 200nm heater line at different noise levels



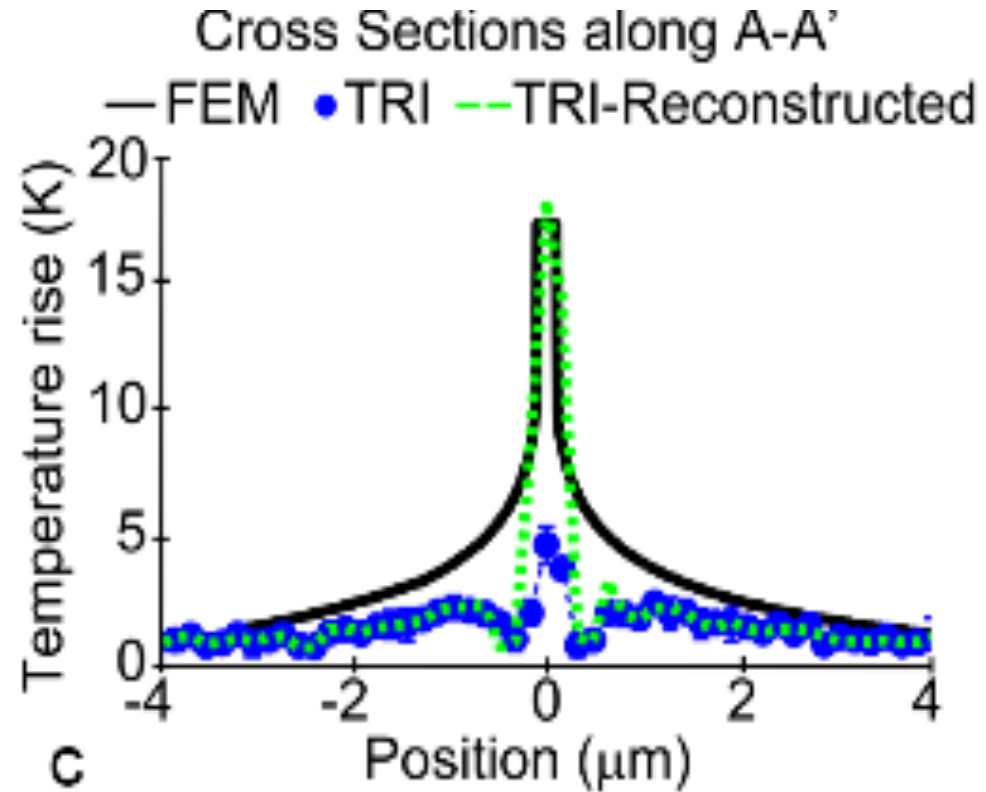
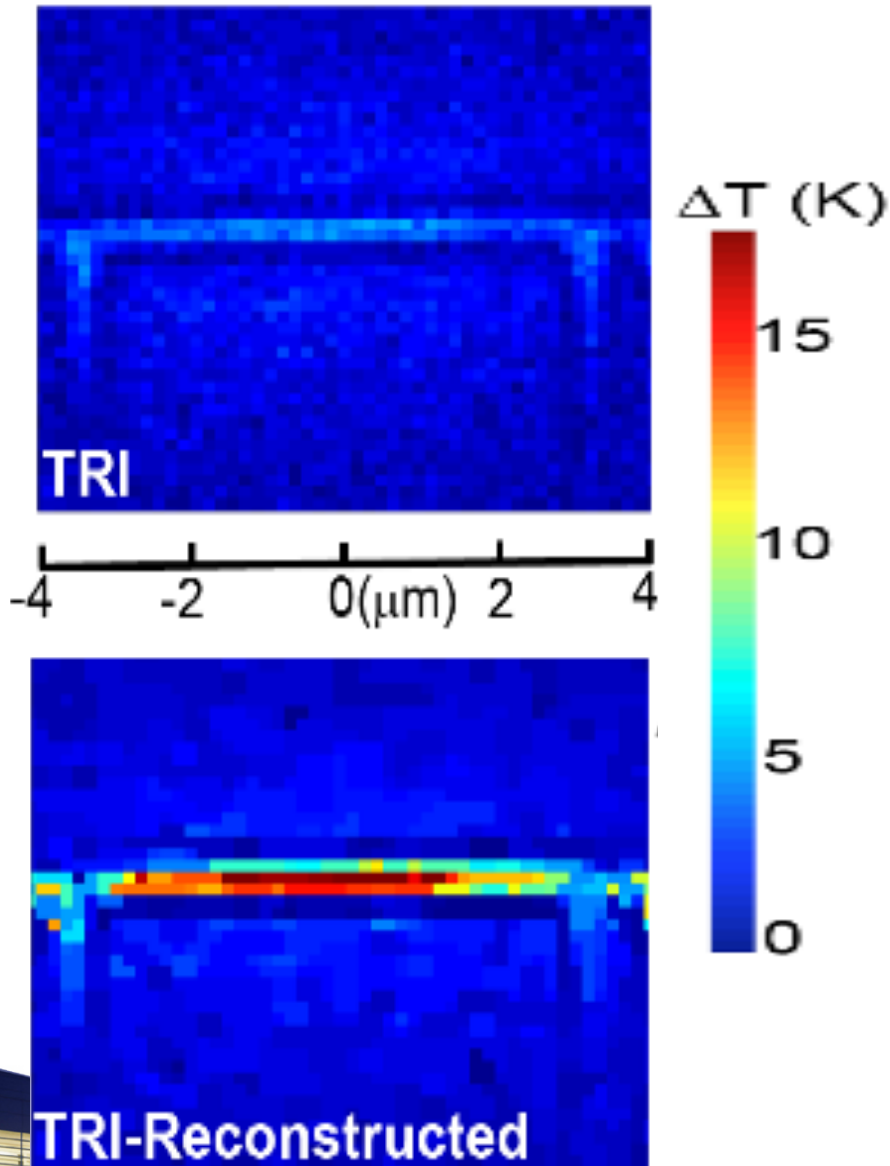
Numerical Experiments

Minimum feature size vs. SNR

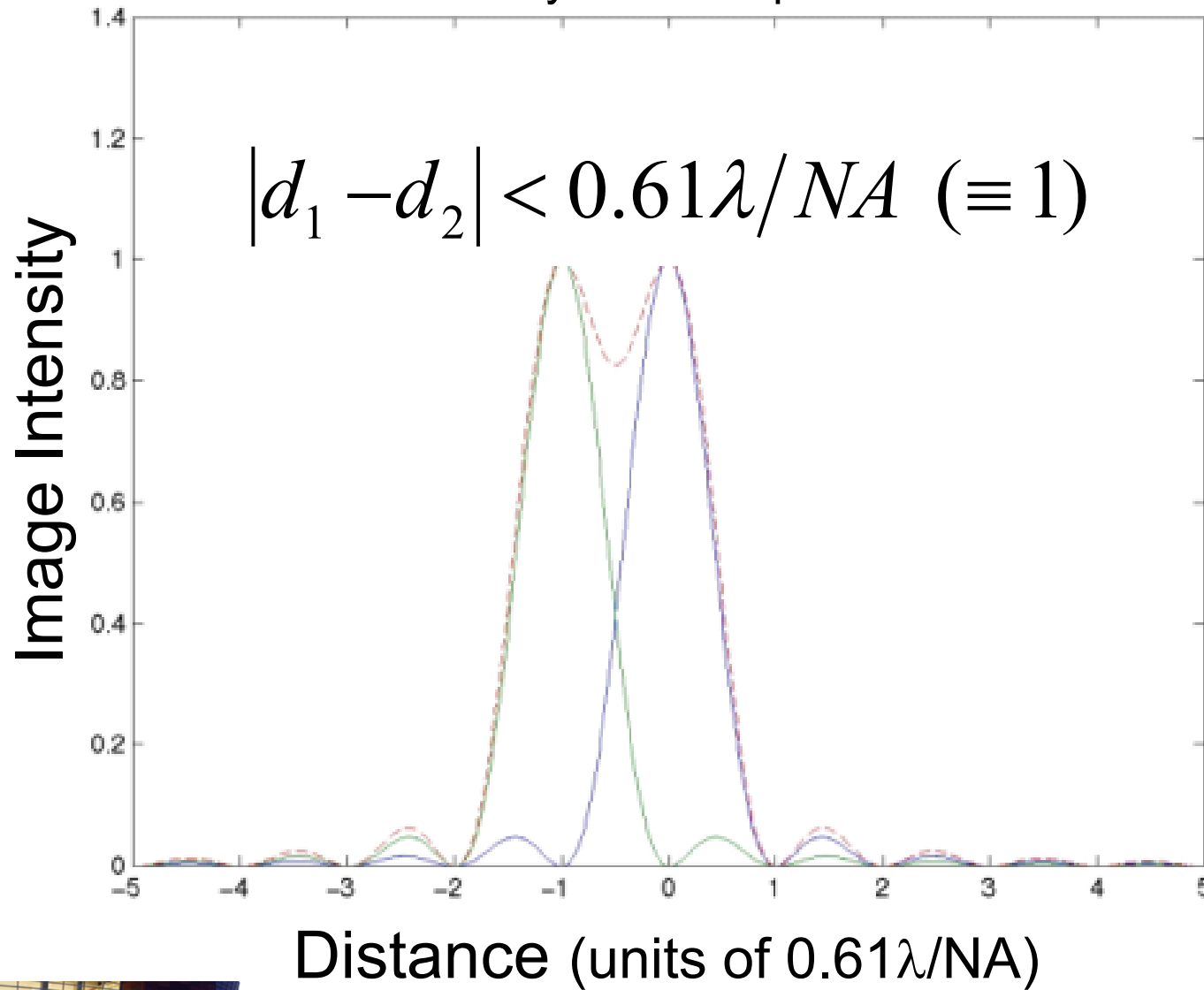


Temperature of features down to 100nm with errors less than 20% reconstructed

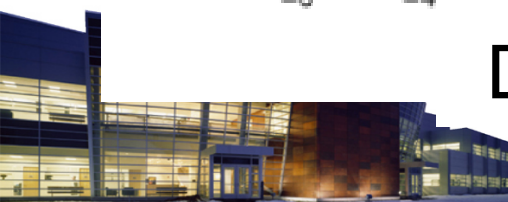




Barely resolved points

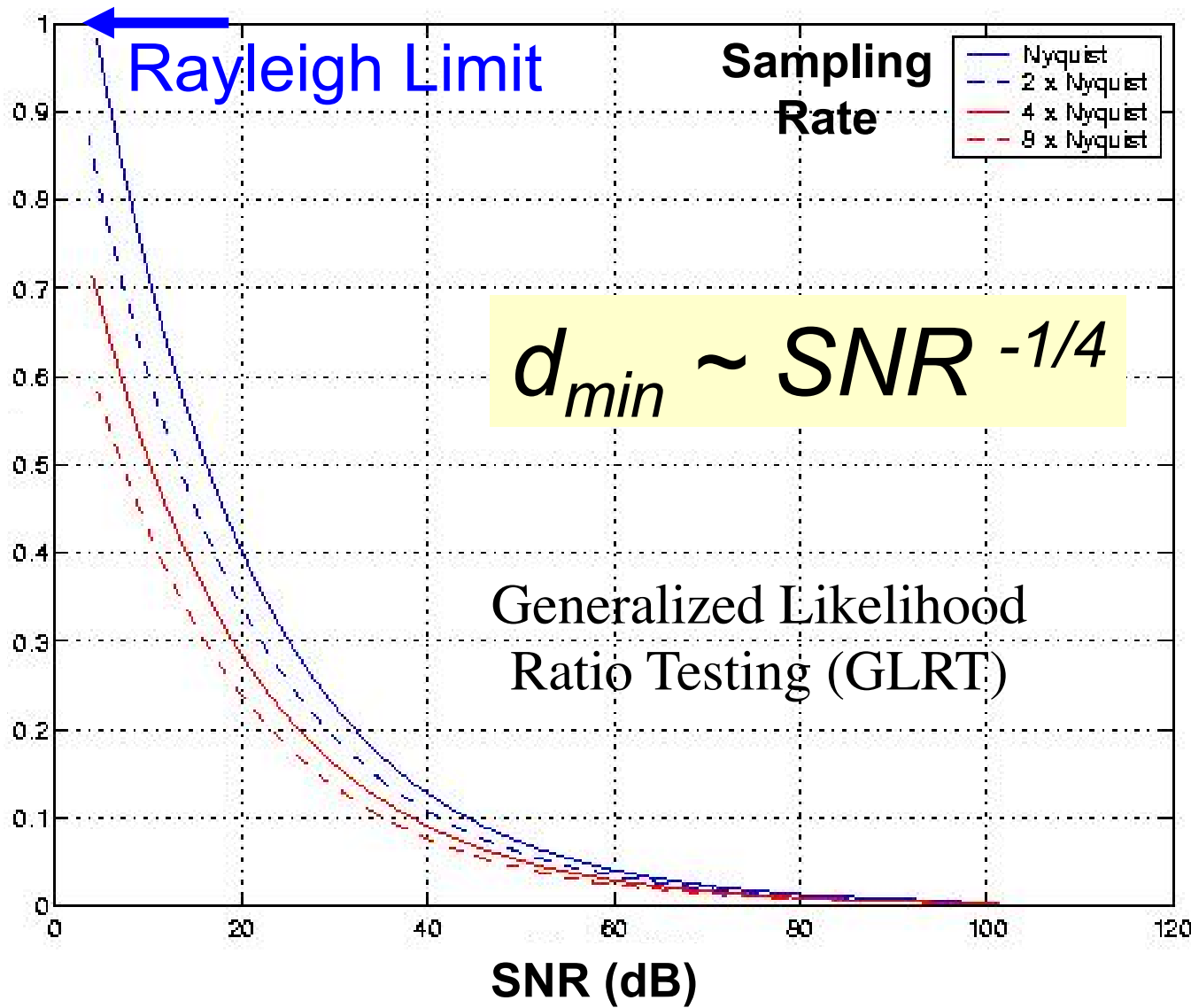


Peyman Milanfar



Minimum Detectable Distance

$P_d = 0.99$
 $P_F = 10^{-6}$



Far-field thermoreflectance imaging

- ❑ Lock-in imaging with mega-pixel CCD Camera (800ps time, 0.01C temperature resolution)
- ❑ Can detect temperature profile of 100-200nm devices
- ❑ Forward image blurring can give accurate temperature map
- ❑ Image reconstruction works for high SNR (need to know optical system parameters, device SEM, and bulk C_{TR})

Question: Can one improve temperature and/or spatial resolution using Quantum + Computations Imaging?